



Model TTP4-1.5K Probe Station

Introduction

The Model TTP4-1.5K is a versatile cryogenic micro-manipulated probe station used for non-destructive testing of devices on full and partial wafers up to 25 mm (1 in) in diameter. The TTP4-1.5K is a platform for measurement of electrical, electro-optical, parametric, high Z, DC, RF, and microwave properties of materials and test devices. Nanoscale electronics, quantum wires and dots, and semiconductors are typical materials measured in a TTP4-1.5K. A wide selection of probes, cables, sample holders, and options makes it possible to configure the TTP4-1.5K to meet your specific measurement applications.

The TTP4-1.5K operates over a temperature range of 1.5 K to 475 K. The probe station provides efficient temperature operation and control with a continuous refrigeration system using either helium or nitrogen. Vapor-cooled shielding optimizes efficiency and intercepts blackbody radiation before it reaches the sample. Two control heaters on the cold head minimize temperature gradients across the sample and, along with the mid-stage and radiation shield heaters, provide the probe station with fast thermal response.

The TTP4-1.5K is user-configured with up to four ultra-stable micro-manipulated stages, each providing precise 3-axis control of the probe position to accurately land the probe tip on device features. Proprietary probe tips in a variety of sizes and materials minimize thermal mass and optimize electrical contacts to the device under test (DUT). Probe tips are thermally linked to the mid-stage to prevent heat transfer to the DUT.

For increased versatility, TTP4-1.5K options include vibration isolation systems, LN₂ Dewar kit, higher magnification monoscopes, vacuum turbo pumping system, and fiber optic probe arm modification.

Features

- High stability operation from 1.5 K to 475 K
- Active cryogenic control of the cold head, mid-stage, and radiation shield
- Reduces potential for sample condensation by allowing sample to remain at room temperature while the system cools to 1.5 K
- Measurements from DC to 67 GHz
- Accommodates up to 25 mm (1 in) diameter wafers
- Configurable with up to four micro-manipulated probe arms
- Probe arms with 3-axis adjustments and $\pm 5^\circ$ theta planarization
- Cables, shields, and guards minimize electrical noise and thermal radiation losses
- High resolution optical system
- Tabletop design with small footprint
- Options and accessories for customization to specific research needs

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Applications

- Electrical and electro-optical measurements over a wide temperature range
- RF and microwave
- Parametric testing
- Shielded/guarded/low noise characterization
- High Z
- Non-destructive, full wafer testing

Materials

- Nanoscale electronics (carbon nanotube transistors, single electron transistors, molecular electronics, nanowires, etc.)
- Quantum wires and dots, quantum tunneling
- Single electron tunneling (Coulomb blockade)
- Basic semiconductor devices including organics, LEDs, and dilute magnetic semiconductors

Specifications

Temperature

Operating temperature range—overall	1.5 K to 475 K*
ZN50 DC/RF probe with low RF cryogenic coax cable	1.5 K to 475 K*
ZN50 DC/RF probe with high RF semirigid coax cable	1.5 K to 400 K*
GSG microwave probe with semirigid coax cable	1.5 K to 400 K*
Temperature control (heaters)	
1.5 K cold head stage	25 W (2 parallel heaters, 12.5 W each)
4.2 K mid-stage	50 W
Radiation shield	100 W
Probe arm	Measurement only

*Selectable equipment

Probe Arm Adjustments

Travel	
X axis	51 mm (2 in)
Y axis	25 mm (1 in)
Z axis	18 mm (0.7 in)
Translation resolution	
X axis	20 μ m
Y and Z axes	10 μ m
Theta planarization*	$\pm 5^\circ$

*Included with microwave probes

Frequency Range

ZN50 DC/RF probe frequency range	
Tungsten with cryogenic coax cable	0 to 50 MHz*
Tungsten with semirigid coax cable	0 to 1 GHz*†
Paliney 7 with cryogenic coax cable	0 to 50 MHz*
Paliney 7 with semirigid coax cable	0 to 1 GHz*†
BeCu with cryogenic coax cable	0 to 50 MHz*
BeCu with semirigid coax cable	0 to 1 GHz*†
GSG microwave probe frequency range	
Low frequency with K connector	0 to 40 GHz*
Mid frequency with 2.4 mm connector	0 to 50 GHz*
High Frequency with 1.8 mm connector	0 to 67 GHz*

*Selectable equipment

† S21 > -10 dB up to 1 GHz, except for a (-40 dB) spike between 400 MHz and 800 MHz depending on probe model and placement; S11 < -3 dB up to 1 GHz

Optical

Optical viewport—located on top lids	Ø54 mm (2.1 in) outer window and Ø51 mm (2 in) inner window
Outer, clear fused quartz	99% IR transmittance
Inner	IR absorbing with narrow band visible light transmittance
Optical resolution—monoscope	
7:1 zoom	5 µm
12.5:1 zoom	4 µm*
16:1 zoom	3 µm*

*Selectable equipment

Sample Holder (Chuck)

Maximum sample size—overall	Up to Ø25 mm (1 in)
SH-1.00-G, grounded chuck	Up to Ø25 mm (1 in) and 475 K
SH-1.00-I, isolated chuck	Up to Ø25 mm (1 in) and 400 K*
SH-1.00-C, coaxial chuck	Up to Ø25 mm (1 in) and 400 K*
SH-1.00-T, triaxial chuck	Up to Ø25 mm (1 in) and 400 K*

*Selectable equipment

Standard Equipment

Open cycle sample stage refrigerator	1.5 K to 475 K
1.5 K cold head stage temperature sensor	Lake Shore Model DT-670-SD-1.4H calibrated silicon diode
1.5 K cold head stage heater	25 W (2 parallel heaters, 12.5 W each)
1.5 K cold head stage rotary pump with oil eliminator and hose	14.7 CFM at 60 Hz
4.2 K mid-stage temperature sensor	Lake Shore Model DT-670C-CU silicon diode
4.2 K mid-stage heater	50 W
Cooled radiation shield and cooled IR-absorbing window above the sample	
Temperature sensor	Lake Shore Model DT-670C-CU silicon diode
Radiation shield heater	100 W
Removable top lid with viewport	Ø51 mm (2 in) window
Temperature controller	Two Lake Shore Model 332S and one Model 142 200 W (2 channels, 100 W each) power supply (independent regulation of 1.5 K cold head stage, 4.2 K mid-stage, radiation shield, and probe arm temperature monitoring)
Vacuum chamber	
Diameter	15.2 cm (6 in)
Removable top lid with clear fused quartz viewport	Ø54 mm (2.1 in) window
Probe ports	4 equally spaced surround the sample thermal radiation shield
Machined aluminum base plate	45.7 cm ² (18 in ²) with four 19.1 cm (7.5 in) legs
Four XYZ precision micro-manipulated probing stages	
Probe arms, thermal radiation shields, stainless steel welded bellows, and feedthrough ports	
Thermally linked probe mounts	Probe mounts and radiation shield are thermally anchored to the mid-stage; one probe mount includes a platinum temperature sensor installed and wired to a 6-pin feedthrough
Grounded sample holder	SH-1.00-G, accommodates up to a Ø25 mm (1 in) sample with a Ø25 mm (1 in) probe area
Optics	
Zoom 70 monoscope	7:1 zoom with 5 µm resolution
Color CCD camera	
Swing arm	Optics can be manipulated to view any part of the sample or wafer, and can be retracted and swung away to allow access to the top of the vacuum chamber for sample exchange
Video monitor	High resolution, 17-inch
Sample illumination	Coaxial via fiber optic or ring light from an adjustable light source and power supply (must specify sample illumination at time of order) NOTE: Coaxial illumination is recommended for highly reflective materials
High efficiency helium transfer line with foot valve for precise flow regulation	
Basic tools, spares, and cleaning kit	

Probes, Probe Tips, and Cables — Required User Configurable Equipment

ZN50 DC/RF PROBES

- Ideal for: DC biasing, low/high frequency measurements, low noise shielded, and low-leakage guarded measurement
- ZN50 probe base incorporates a pair of copper braids that connect to the sample stage to dynamically cool/heat the probe to the sample temperature
- SMA connector mounted directly to a replaceable alumina ceramic blade with a 50 Ω stripline routed to the probe contact

We understand that today's researcher requires flexibility. Our wide selection of probes, cables, sample holders, and options make it possible to configure a probe station to meet your specific measurement applications.

Part number (probe body)	Description
ZN50-26U	50 Ω stripline probe body mount (each probe body mount requires a ceramic blade—selectable below)

Part number (ceramic blade)	Tip material	Maximum frequency (GHz)	Tip radius (μm)
ZN50R-03-W	Tungsten	1*	3
ZN50R-10-W			10
ZN50R-25-W			25
ZN50R-03-P7	Paliney 7		3
ZN50R-10-P7			10
ZN50R-25-P7			25
ZN50R-03-BeCu	BeCu		3
ZN50R-10-BeCu			10
ZN50R-25-BeCu			25
ZN50R-100-BeCu			100
ZN50R-200-BeCu			200

*Maximum frequency 50 MHz with Z50-CU-SS-3650-G or Z50-CU-SS-3650-T cable; maximum frequency 1 GHz with K-085-K cable

ZN50 DC/RF CABLES

Part number	Cable type	Connector type	Feedthrough type	Measurement configuration	Maximum frequency	Maximum temperature
Z50-CU-SS-3650-G	Ultra-miniature cryogenic coax	SMA	BNC	Shielded	50 MHz	475 K
Z50-CU-SS-3650-T	Ultra-miniature cryogenic coax	SMA	2-lug triax	Low leakage	50 MHz	475 K
K-085-K-07	Stainless semirigid microwave coax	K	Loss-less compression seal	High frequency	1 GHz*	400 K

* S21 > -10 dB up to 1 GHz, except for a (-40 dB) spike between 400 MHz and 800 MHz depending on probe model and placement; S11 < -3 dB up to 1 GHz

GSG MICROWAVE PROBES

- Coplanar waveguide probe with ground-signal-ground (GSG) contact geometry
- User specified pitch (spacing)
- Optimized low thermal conductivity coax leading to low thermal conductivity tips
- Includes a copper braid assembly to cool the probe to near sample temperature
- Probes are limited to 400 K
- A separate theta planarization module with $\pm 5^\circ$ rotation mechanism is also provided

Part Number	Connector Type	Maximum Frequency (GHz)	Pitch (μm)
GSG-050-40A-26U-D	K	40	50
GSG-100-40A-26U-D			100
GSG-150-40A-26U-D			150
GSG-200-40A-26U-D			200
GSG-250-40A-26U-D			250
GSG-050-50A-26U-D	2.4 mm	50	50
GSG-100-50A-26U-D			100
GSG-150-50A-26U-D			150
GSG-200-50A-26U-D			200
GSG-250-50A-26U-D			250
GSG-050-67A-26U-D	1.8 mm	67	50
GSG-100-67A-26U-D			100
GSG-150-67A-26U-D			150
GSG-200-67A-26U-D			200
GSG-250-67A-26U-D			250

GSG MICROWAVE CABLES

- Loss-less compression seal
- Semirigid with stainless steel outer jacket, silver plated BeCu inner conductor, and Teflon® dielectric

Part number	Cable type	Feedthrough type	Maximum temperature	Connector type	Maximum frequency
K-085-K-07	Stainless semirigid microwave coax	Loss-less compression seal	400 K	K	40 GHz
2.4-085-2.4-07				2.4 mm	50 GHz
1.8-085-1.85-07				1.8 mm	67 GHz

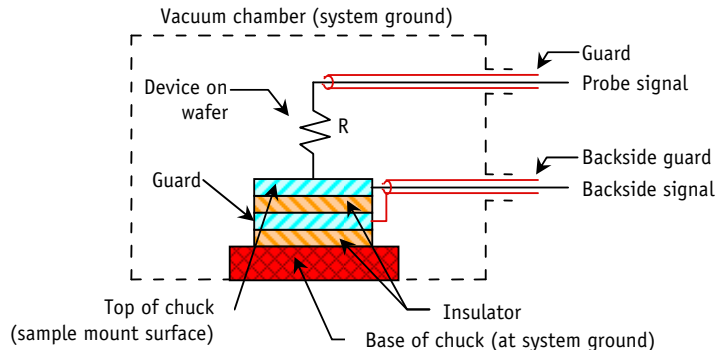
SAMPLE HOLDERS (CHUCKS)

Typical sample holder configuration characterized by:

- Leakage resistance between
 - Top surface and guard
 - Guard and ground
- Capacitance between
 - Top surface and guard
 - Guard and ground

Types of sample holders

- Grounded sample holder—sample mount surface at system ground
- Isolated sample holder—backside contact not needed; sample mount surface is electrically non-conductive and isolated from ground
- Coaxial sample holder—backside contact can be made; sample mount surface is isolated from ground
- Triaxial sample holder—guarded backside contact can be made; sample mount surface has guarded isolation from ground



Part number	Measurement configuration	Separate feedthrough required	Maximum sample (diameter)	Maximum temperature
SH-1.00-G	Grounded	No	Ø25 mm (1 in)	475 K
SH-1.00-I	Isolated			400 K
SH-1.00-C	Coaxial	Yes*		
SH-1.00-T	Triaxial	Yes**		

*Coaxial sample holders require one FT-BNC or FT-TRIAX feedthrough as listed below

**Triaxial sample holders require one FT-TRIAX feedthrough as listed below

Part number	Description
FT-BNC	Coaxial feedthrough and coax cable, installed and wired
FT-TRIAX	Triaxial feedthrough and coax cable, installed and wired

Equipment Options

Part Number	Description
PS-FOA	Fiber optic probe arm modification. Transmit or receive light or IR/UV radiation. Fiber optic terminated with SMA connector or compression feedthrough. (Fiber optic wire not included. Fiber optic and probe cannot be used simultaneously.)
PS-Z12.5	12.5:1 zoom monoscope upgrade for 4 µm resolution NOTE: upgrade is not field-installable
PS-Z16	16:1 zoom monoscope upgrade for 3 µm resolution NOTE: upgrade is not field-installable
PS-DPC	Automatic Dewar (gas) pressure controller, regulates Dewar liquid flow
PS-V81TP	Turbo pumping system—includes Varian V-81 Turbo Pump cart with DS 102 backing pump, vacuum gauging for high vacuum and fore line, controller, and adaptors (specify 110 V/60 Hz or 220 V/50 Hz)
PS-V81DP	Turbo pumping system—includes Varian V-81 Turbo Pump cart with oil free backing pump, vacuum gauging for high vacuum and fore line, controller, and adaptors (specify 110 V/60 Hz or 220 V/50 Hz)
PS-LN2	Nitrogen Dewar with stainless fittings, gauges, and adaptors; allows LN ₂ use with the LHe transfer line
PS-PLVI-25	Pump-line vibration isolator—includes NW-25 fittings, 1 m stainless steel bellows, clamps, and rings (placed between pump cart and system); requires one bag of cement
PS-LVS	Low vibration, heavy PVC constructed non-magnetic stand with sand weighted legs and brass fittings NOTE: this option minimizes system vibration displacement at all frequencies
PS-TTVIS	Pneumatic tabletop vibration isolation system—compact pneumatic isolator with self-leveling (isolator resonance: vertical 3.2 Hz, horizontal 3.6 Hz; isolation efficiency at 10 Hz: vertical 90%, horizontal 96%; amplification at resonance: vertical 12 dB, horizontal 10 dB); requires PS-LVS (ordered separately) and 80 psi nitrogen or air
PS-OAC	Oil-less compressor for PS-TTVIS (only available in 110 V)
PA-SEN	Probe arm modification with platinum temperature sensor installed and wired to a 6-pin feedthrough

Equipment Options, continued

PA-TTP4	Probe arm and base for TTP4-1.5K
MMS-TTP4	Micro-manipulated stage for TTP4-1.5K
CS-5	Calibration substrate for GSG probes. Pad size: 50 μm^2 ; calibration type: SOLT (short-open-load-through), LRL (line-reflective-line), LRM (line-reflective-match); pitch range: 75 to 250 μm
CS-15	Calibration substrate for GSG probes. Pad size: 25 μm^2 ; calibration type: SOLT (short-open-load-through), LRL (line-reflective-line), LRM (line-reflective-match); pitch range: 40 to 150 μm

Lake Shore Cryotronics is a leading supplier of cryogenic, superconducting magnet-based, electromagnet-based, high vacuum, and load-lock probe stations. We offer a full line of standard probe stations to meet your research requirements.

Our standard line of probe stations includes:

Model TTP4

- Up to four micro-manipulated probe stages
- Temperature range capabilities from 3.2 K to 475 K
- Up to 51 mm (2 in) diameter wafer capabilities

Model TTP4-1.5K

- Up to four micro-manipulated probe stages
- Standard temperature range from 1.5 K to 475 K
- Up to 25 mm (1 in) diameter wafer capabilities

Model TTP6

- Up to six micro-manipulated probe stages
- Temperature range capabilities from 3.2 K to 475 K
- Up to 51 mm (2 in) diameter wafer capabilities

Model FWP6

- Up to six micro-manipulated probe stages
- Standard temperature range from 4.5 K to 475 K
- Up to 10.2 cm (4 in) diameter wafer capabilities

Model LLTP6

- Load-lock — for fast sample exchange at any temperature
- Up to six micro-manipulated probe stages
- Standard temperature range from 10 K to 400 K
- Up to 51 mm (2 in) diameter wafer capabilities; up to 12.7 mm (0.5 in) with load-lock assembly

Model HFTP4

- 1 T horizontal field split pair superconducting magnet
- Up to four micro-manipulated probe stages
- Temperature range capabilities from 2 K to 400 K with field on or off
- Up to 25 mm (1 in) diameter wafer capabilities

Model VFFTP4

- 2.5 T vertical field solenoid superconducting magnet
- Up to four micro-manipulated probe stages
- Temperature range capabilities from 2 K to 400 K with field on or off
- Up to 51 mm (2 in) diameter wafer capabilities

Model EMFTP4

- 0.55 T horizontal (in-plane field) electromagnet
- Up to four micro-manipulated probe stages
- Standard temperature range from 5 K to 475 K
- Up to 25.4 mm (1 in) diameter wafer capabilities

Model HVFTP6

- High vacuum to 10^{-7} torr
- Up to six micro-manipulated probe stages
- Temperature range capabilities from 2 K to 475 K
- Up to 51 mm (2 in) diameter wafer capabilities